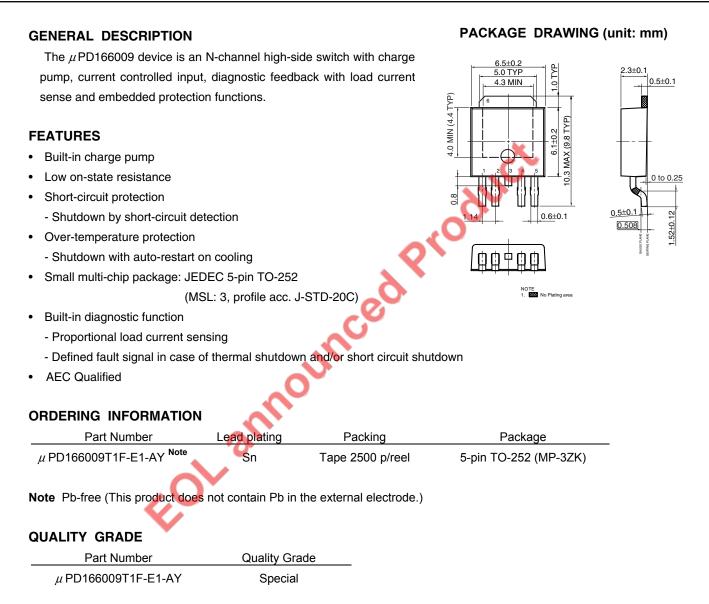


MOS INTEGRATED CIRCUIT $\mu PD166009$

SINGLE N-CHANNEL HIGH SIDE INTELLIGENT POWER DEVICE



Please refer to "Quality Grades on NEC Semiconductor Devices" (Document No. C11531E) published by NEC Corporation to know the specification of quality grade on the devices and its recommended applications.

APPLICATION

- Light bulb (to 55 W) switching
- Switching of all types of 14 V DC grounded loads, such as inductor, resistor and capacitor
- · Replacement for fuse and relay

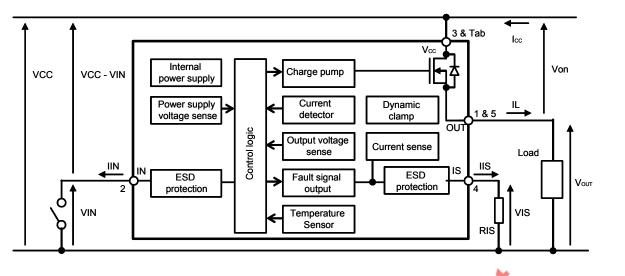
The information in this document is subject to change without notice. Before using this document, please confirm that this is the latest version. Not all products and/or types are available in every country. Please check with an NEC Electronics sales representative for availability and additional information.

The mark <R> shows major revised points.

© NEC Electronics Corporation 2009

The revised points can be easily searched by copying an "<R>" in the PDF file and specifying it in the "Find what:" field.

BLOCK DIAGRAM



PIN CON	FIGURATION		Č.	Tab
Pin No.	Terminal Name	Function		
1	OUT	Output to load: pin 1 and 5 must be externally shorted.		
2	IN	Input; activates the power switch, if shorted to ground.		
3	Vcc	Supply Voltage: tab and pin 3 are internally shorted.		12345
4	ls	Sense Output: diagnostic feedback		
5	OUT	Output to load: pin 1 and 5 must be externally shorted.		

Note If current sense and diagnostic features are not used, IS terminal has to be connected to GND via resistor.

Data Sheet S19688EJ2V0DS

Parameter	Symbol		Test Conditions	Rating	Unit
Vcc voltage	Vcc1			28	V
Vcc voltage (Load Dump)	Vcc2	-	R∟ = 1.5 Ω, t₀ = 400 ms, IN = low or high	40	V
Vcc voltage (Reverse polarity)	-Vcc	R∟ = 2.2 Ω,	, 1 minute	-16	V
Load current	l.	DC, Tc = 2	5°C	30	А
Load current (short circuit current)	IL(SC)			Self Limited	A
Power dissipation	PD	Tc = 25°C		59	W
Inductive load switch-off energy dissipation single pulse	Eası	I∟ = 10 A, V refer to pag	/cc = 12 V, Tch,start ≤ 150°C, ge 16	50	mJ
Maximum allowable energy under over load condition (Single pulse)	Eas2		, Tch,start \leq 150°C, R _{supply} = 10 mΩ, mΩ, L _{supply} = 5 μ H, L _{short} = 15 μ H, ge 16	105	mJ
Channel temperature	Tch			_40 to +150	°C
Storage temperature	Tstg			-55 to +150	°C
Electric discharge capability	Vesd	НВМ	AEC-Q100-002 std. R = 1.5 kΩ, C = 100pF	2000	V
		ММ	AEC-Q100-003 std. R = 0 Ω, C = 200pF	400	V
Voltage of IN pin	VIN	DC	0	Vcc-28 V	V
Reverse polarity condition, 1 minute		plarity condition, 1 minute	Vcc+14 V	V	
Voltage of IS pin	Vis	DC		Vcc-28 V	V
		Reverse po	plarity condition, 1 minute	Vcc+14 V	V

ABSOLUTE MAXIMUN	RATING	(Ta = 25°C	, unless otherwise s	pecified)
------------------	--------	------------	----------------------	-----------

RECOMMENDED OPERATING CONDITIONS

Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Power supply voltage	Vcc 🧖	T _{ch} = −40 to 150°C	8	-	18	V

Cautions 1. It is assumed that VIN= 0 V when the device is activated.

2. Device operating range is limited by energy dissipation capability of the driver. User must carefully consider worst case load and current conditions in combination of operating voltage.

THERMAL CHARACTERISTICS

Parameter	Symbol	Test Conditions		Тур.	Max.	Unit
Thermal resistance	Rth(ch-a)	Device on 50 mm x 50 mm x 1.5 mmt epoxy PCB FR-4 with 6 cm ² of 70 μ m copper area		45	55	°C/W
	Rth(ch-c)		_	-	3.17	°C/W

ELECTRICAL CHARACTERISTICS (Vcc = 12 V, Tch = 25°C, unless otherwise specified)

Parameter	Symbol	Test Conditions		Min.	Тур.	Max.	Unit
Required current capability of Input switch	Ін	$T_{ch} = -40$ to $150^{\circ}C$		-	1.0	2.2	mA
Input current for turn-off	lı∟			_	_	50	μA
Standby current	ICC(off)	$I_{IN} = 0 A $		-	2.5	5.0	μA
				_	2.5	15.0	μA
On state resistance	Ron	I∟ = 7.5 A	$T_{ch} = 25^{\circ}C$	_	8	10	mΩ
			$T_{ch} = 150^{\circ}C$	_	14	18	
Turn on Time	ton	RL = 2.2 Ω,		_	200	500	μs
Turn off Time	toff	$T_{ch} = -40$ to 150°C, refer to page 15		_	250	600	μs
Slew rate on	dV/dton	25 to 50% V _{OUT} , R_L = 2.2 Ω,		_	0.2	0.6	V/µs
		$T_{ch} = -40$ to 150°C, refer to page 15					
Slew rate off	-dV/dtoff	50 to 25% Voυτ, RL = 2.2 Ω,		_	0.2	0.5	V/µs
		$T_{ch} = -40$ to $150^{\circ}C$, r	efer to page 15		X		

-2Ω . o 150°C, refer to page 15

PROTECTION FUNCTIONS (Vcc = 12 V, Tch = 25°C, unless otherwise specified)

Parameter	Symbol	Test C	onditions	Min.	Тур.	Max.	Unit
On-state resistance at reverse battery condition	Ron(rev)	Vcc = −12 V, I _L = − < 150 Ω	7.5 A, Rıs = 1 kΩ, RıN				
			$T_{ch} = 25^{\circ}C$		9.5	13	mΩ
			T _{ch} = 150°C	_	16	22	mΩ
Short circuit detection current	Note	$V_{\rm CC} - V_{\rm IN} = 6 V$,	$T_{ch} = -40^{\circ}C$	_	50	120	Α
	-, - ()	Von = 3 V	T _{ch} = 25°C	_	50	_	
			$T_{ch} = 150^{\circ}C$	20	45	_	
	Note	$V_{\rm CC} - V_{\rm IN} = 6 V$,	$T_{ch} = -40^{\circ}C$	-	35	110	
	120, 0(30)	$V_{on} = 6 V$	$T_{ch} = 25^{\circ}C$	_	35	_	
			$T_{ch} = 150^{\circ}C$	10	35	_	
	L12, 3(SC)	$V_{CC} - V_{IN} = 12 V$,	$T_{ch} = -40^{\circ}C$	10	110	180	
	IL12, 3(SC)	$V_{cc} = V_{IN} = 12 V$, $V_{on} = 3 V$		76	105		
		Von – C V	$T_{ch} = 25^{\circ}C$	76		—	
	, Note	<u> </u>	$T_{ch} = 150^{\circ}C$	50	95	-	
	L12, 6(SC)	$V_{CC} - V_{IN} = 12 V,$ $V_{on} = 6 V$	$T_{ch} = -40^{\circ}C$		90	160	
		\mathbf{v} on = \mathbf{O} \mathbf{v}	$T_{ch} = 25^{\circ}C$		8 5	-	
	, Note		$T_{ch} = 150^{\circ}C$	40	80	-	
	L12, 12(SC)	$V_{CC} - V_{IN} = 12 V$,	$T_{ch} = -40^{\circ}C$	<u> </u>	55	120	
		Von = 12 V	T _{ch} = 25°C	_	50	-	
	, Note		T _{ch} = 150°C	10	45	-	
	IL18, 3(SC)	$V_{CC} - V_{IN} = 18 V$,	Tch = -40°C	—	130	200	
		Von = 3 V	$T_{ch} = 25^{\circ}C$	_	125	-	
		6	Tch = 150°C	60	110	-	
	Note	$V_{CC} - V_{IN} = 18 V$,	$T_{ch} = -40^{\circ}C$	_	110	170	
		Von = 6 V	$T_{ch} = 25^{\circ}C$	_	110	-	
			$T_{ch} = 150^{\circ}C$	50	100	-	
	Note	$V_{CC} - V_{IN} = 18 V,$	$T_{ch} = -40^{\circ}C$	-	75	120	
		Von = 12 V	$T_{ch} = 25^{\circ}C$	-	70	-	
			$T_{ch} = 150^{\circ}C$	30	65	-	
	L18, 18(SC)	$V_{CC} - V_{IN} = 18 V$,	$T_{ch} = -40^{\circ}C$	-	50	90	
	\sim	Von = 18 V	$T_{ch} = 25^{\circ}C$	_	50	-	
)`		T _{ch} = 150°C	5	45	_	
Output clamp voltage (inductive load switch off)	Von(CL)	$I_L = 40 \text{ mA}, T_{ch} = -$	-40 to 150°C	30	34	40	V
Over load detection voltage	Von(OvL)	T _{ch} = -40 to 150°C	;	0.65	1	1.45	V
Turn-on check delay after input current positive slope	td(OC)	$T_{ch} = -40$ to $150^{\circ}C$;	0.9	2.1	3.8	ms
Under voltage shutdown	VCIN(Uv)	$T_{ch} = -40^{\circ}C$		_	_	5.8	v
-		T _{ch} = 25°C		3.6	4.5	5.4	V
		T _{ch} = 150°C		3.2	_	_	V
Under voltage restart of		$T_{ch} = -40^{\circ}C$		_	_	6.5	V
charge pump		$T_{ch} = 25^{\circ}C$		4.1	5.1	6.0	V
		$T_{ch} = 150^{\circ}C$		3.7		_	v
Thermal shutdown temperature	Tth			150	175	_	°C

Note Not subject to production test, specified by design.

DIAGNOSTIC CHARACTERISTICS (Vcc = 12 V, Tch = 25°C, unless otherwise specified)

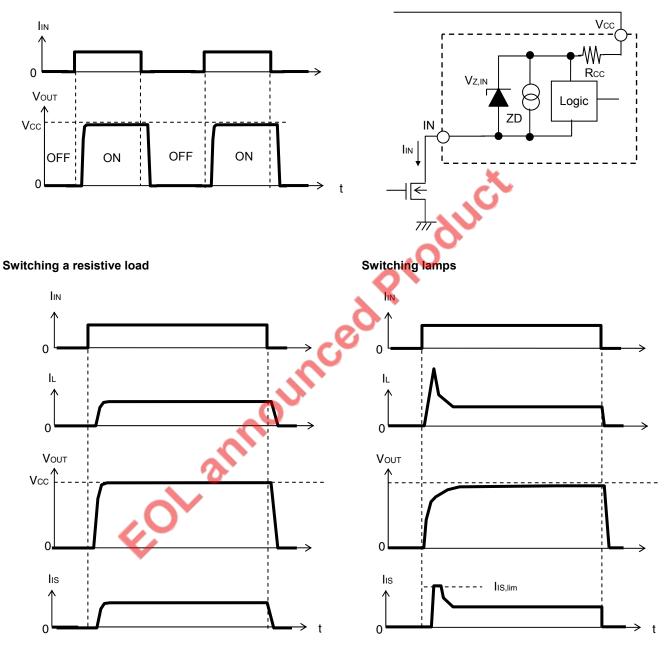
Parameter	Symbol	Test Co	onditions	Min.	Тур.	Max.	Unit
Current sense ratio	Kilis	Kilis = Il∕Iis Vis < Vout – 6 V, Iis	< Iıs,lim				
		I∟ = 30 A	$T_{ch} = -40^{\circ}C$	8300	9350	10800	
			$T_{ch} = 25^{\circ}C$	8300	9400	10600	
			$T_{ch} = 150^{\circ}C$	8300	9450	10000	
		I∟ = 7.5 A	$T_{\text{ch}} = -40^{\circ}C$	7500	9400	11400	
			$T_{ch} = 25^{\circ}C$	8000	9500	10800	
			$T_{\text{ch}} = 150^{\circ}C$	8200	9550	10200	
		I∟ = 2.5 A	$T_{\text{ch}} = -40^{\circ}C$	6100	9600	14200	
			$T_{ch} = 25^{\circ}C$	6500	9600	12800	
			$T_{\text{ch}} = 150^{\circ}C$	7600	9600	11500	
Sense current offset current	IS,offset	$V_{\text{IN}}=0~V,~I_{\text{L}}=0~A$		0	_	60	μA
Sense current under fault	IS,fault	Under fault condition	ons	3.5	6.0	12.0	mA
condition		8 V < Vcc - Vis < 12	2 V,		9		
Sense current saturation current	IIS,lim	$T_{ch} = -40 \text{ to } 150^{\circ}\text{C}$ $V_{is} < V_{out} - 6 \text{ V},$ $T_{ch} = -40 \text{ to } 150^{\circ}\text{C}$, C	3.5	7.0	12.0	mA
Fault sense signal delay after short circuit detection	tsdelay(fault)	$T_{ch} = -40$ to 150°C	, 9	-	2	6	μs
Sense current leakage current	lis(LL)	IIN = 0 A	0	-	0.1	0.5	μA
Current sense settling time after input current positive slope	tson(IS)	T _{ch} = −40 to 150°C I _L = 0 A 20 A		_	250	1000	μs
Current sense settling time during on condition	Tsic(IS)	T _{ch} = -40 to 150°C I⊾ = 10 A 20 A	,	-	50	100	μs

Note Not subject to production test, specified by design.

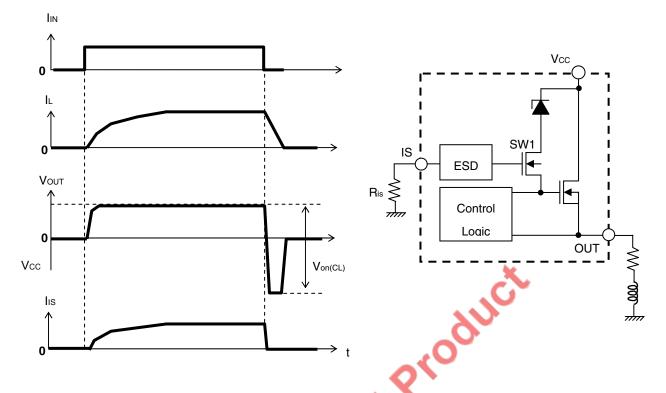
FEATURES DESCLIPTION

Driver Circuit (On-Off Control)

The high-side output is turned on, if the input pin is shorted to ground. The input current is below I_{IH}. The high-side output is turned off, if the input pin is open or the input current is below I_{IL}. R_{CC} is 100 Ω typ. ESD protection diode: 46 V typ.



Switching an inductive load



Dynamic clamp operation at inductive load switch off

The dynamic clamp circuit works only when the inductive load is switched off. When the inductive load is switched off, the voltage of OUT falls below 0 V. The gate voltage of SW1 is then nearly equal to GND because the IS terminal is connected to GND via an external resister. Next, the voltage at the source of SW1 (= gate of output MOS) falls below the GND voltage. SW1 is turned on, and the clamp diode is connected to the gate of the output MOS, activating the dynamic clamp circuit.

When the over-voltage is applied to Vcc, the gate voltage and source voltage of SW1 are both nearly equal to GND. SW1 is not turned on, the clamp diode is not connected to the gate of the output MOS, and the dynamic clamp circuit is not activated.

Short circuit protection

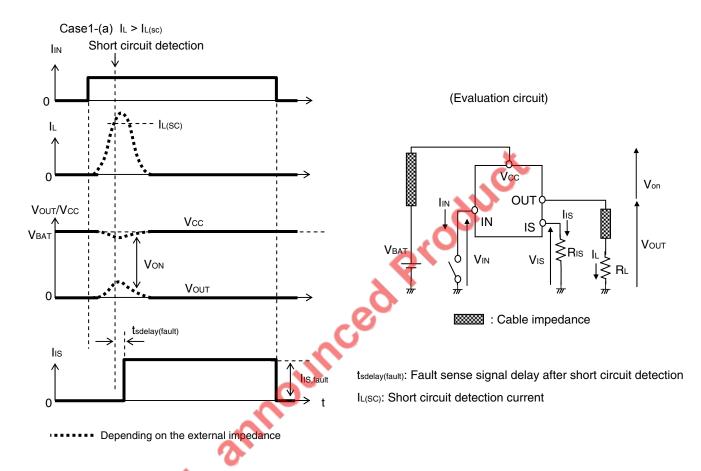
Case 1: IN pin is shorted to ground in an overload condition, which includes a short circuit condition.

The device shuts down automatically when either or both of following conditions (a, b) is detected.

The sense current is fixed at IIS, fault. Shutdown is latched until the next reset via input.

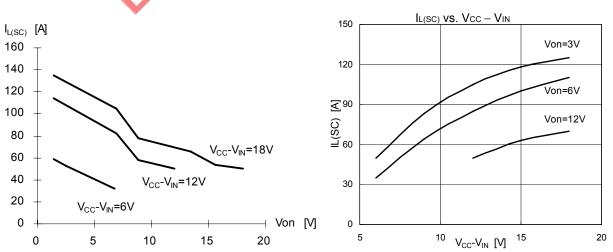
(a) $I_L > I_{L(sc)}$

(b) $Von > V_{on(OvL)}$ after $t_{d(OC)}$

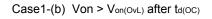


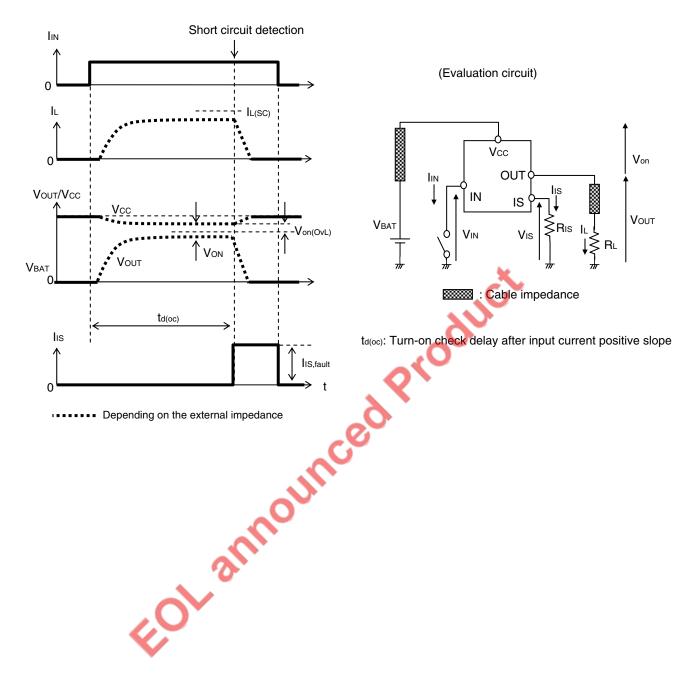
Typical Short circuit detection current characteristics

The short circuit detection current changes according Vcc voltage and Von voltage for the purpose of to be strength of the robustness under short circuit condition.



NEC





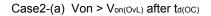
NEC

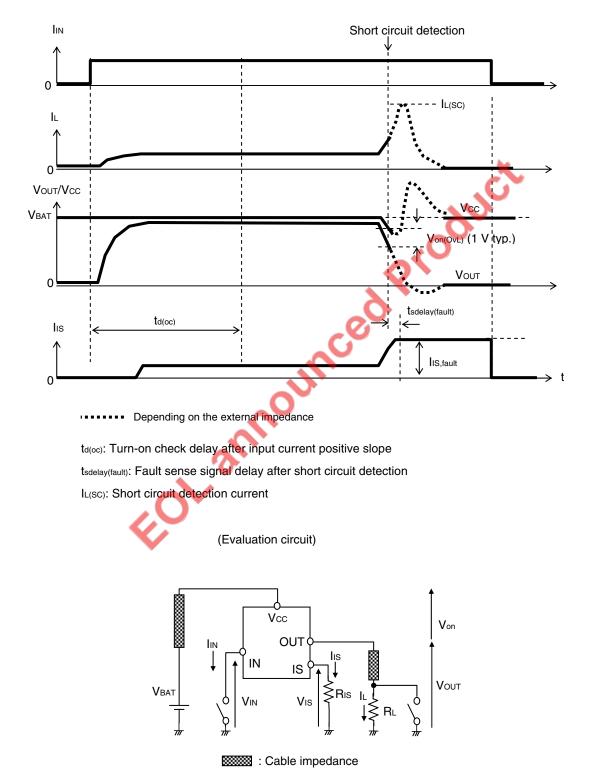
Case 2: Short circuit during on-condition

The device shuts down automatically when either or both of following conditions (a) is detected.

The sense current is fixed at lis,fault. Shutdown is latched until the next reset via input.

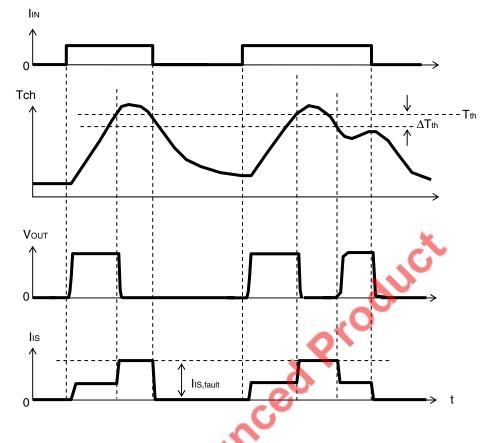
(a) Von > Von(OvL) after td(oc)





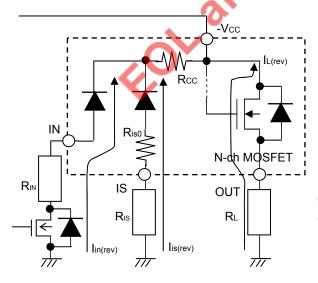
Over-temperature protection

The output is switched off if over-temperature is detected. The device switches on again after it cools down.



Power dissipation under reverse battery condition

In case of reverse battery condition, the internal N-ch MOSFET is turned on to reduce the power dissipation caused by the body diode. Additional power is dissipated by the internal resisters. Following is the formula for estimation of total power dissipation Pd(e) in reverse battery condition.



 $Pd(rev) = Ron(rev) \times IL(rev)^2$

$$\begin{split} + & (Vcc - V_f - I_{in(rev)} \times R_{IN}) \times I_{in(rev)} \\ + & (Vcc - I_{is(rev)} \times R_{IS}) \times I_{is(rev)} \\ & I_{in(rev)} = & (Vcc - 2 \times V_f) / (Rcc + R_{IN}) \\ & I_{is(rev)} = & (Vcc - V_f) / (Rcc + R_{is0} + R_{IS}) \end{split}$$

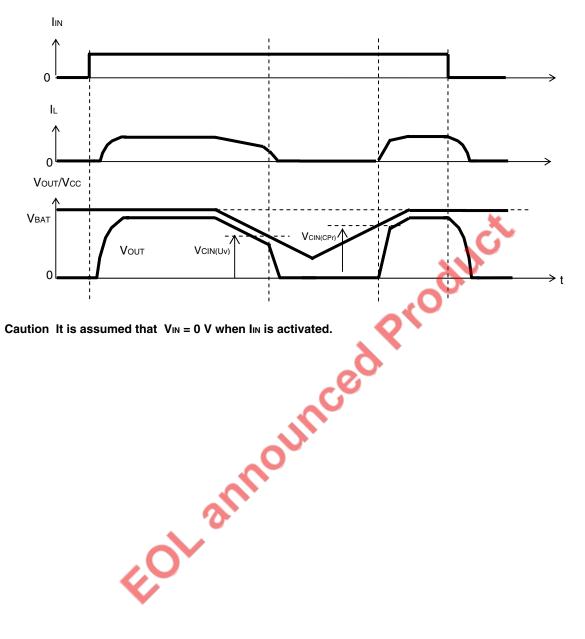
The reverse current through the N-ch MOSFET has to be limited by the connected load.

In order to turn on the N-ch MOSFET at reverse polarity condition, the voltage at IN should be around 8 V by using a MOSFET or small diode in parallel to the input switch. RIN should be estimated following formula.

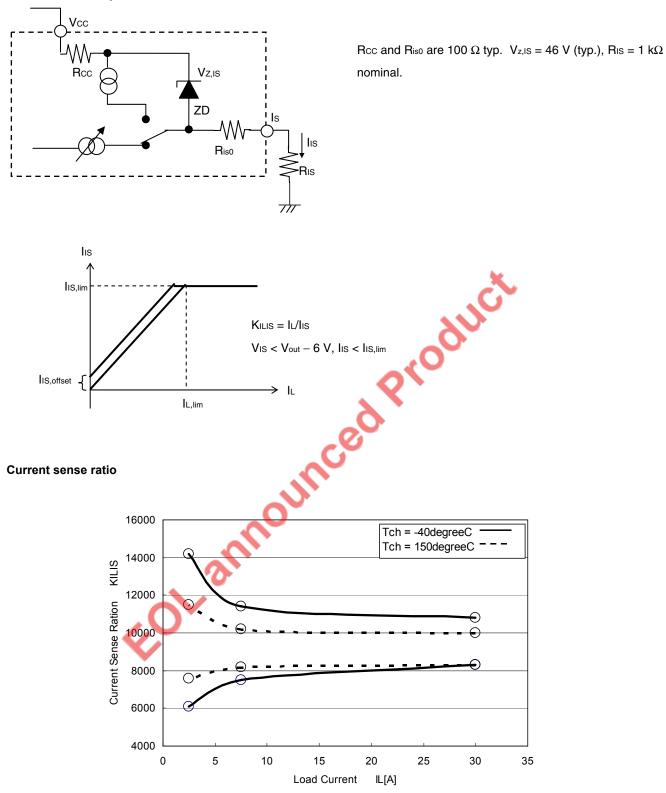
$$R_{IN} < (|V_{CC}| - 8 V) / 0.08 A$$

Device behavior at low voltage condition

If the supply voltage (Vcc - VIN) goes below VCIN(UV), the device shuts off the output. If supply voltage (Vcc - VIN) increases above VCIN(CPr), the device turns on the output automatically. The device stays off if supply voltage (Vcc - VIN) does not increase above VCIN(CPr) after an under voltage shutdown.

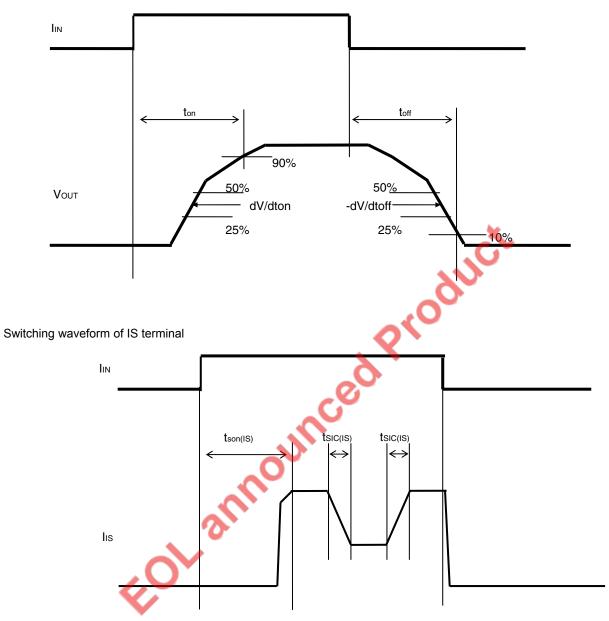


Current sense output



Measurement condition

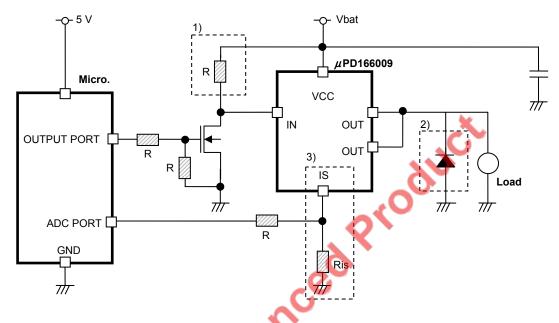
Switching waveform of OUT Terminal



Truth table

Input Current	State	Output	Sense Current
L	_	OFF	lis(ll)
	Normal Operation	ON	IL/KILIS
Н	Over-temperature or Short circuit	OFF	IS,fault
	Open Load	ON	IS,offset

<R> Application example in principle

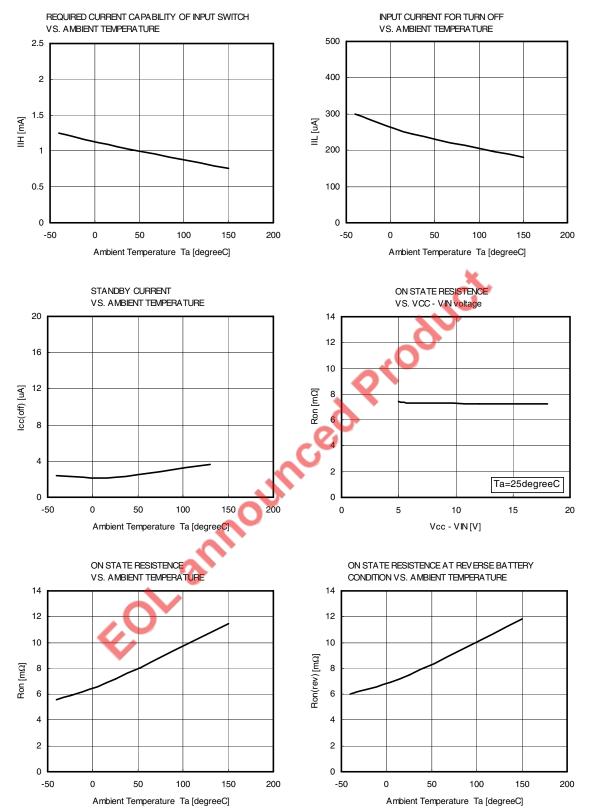


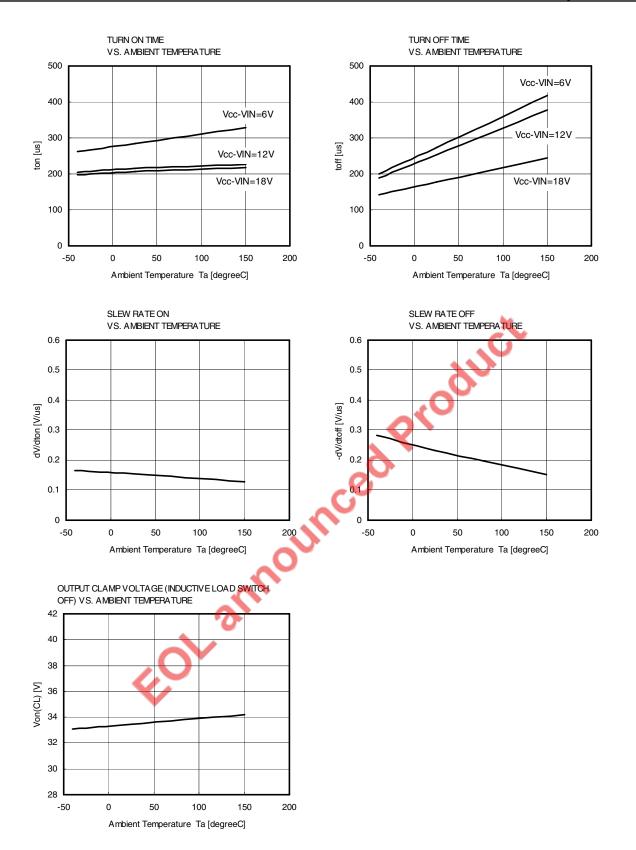
1) In order to prevent leakage current through at IN terminal via PCB,

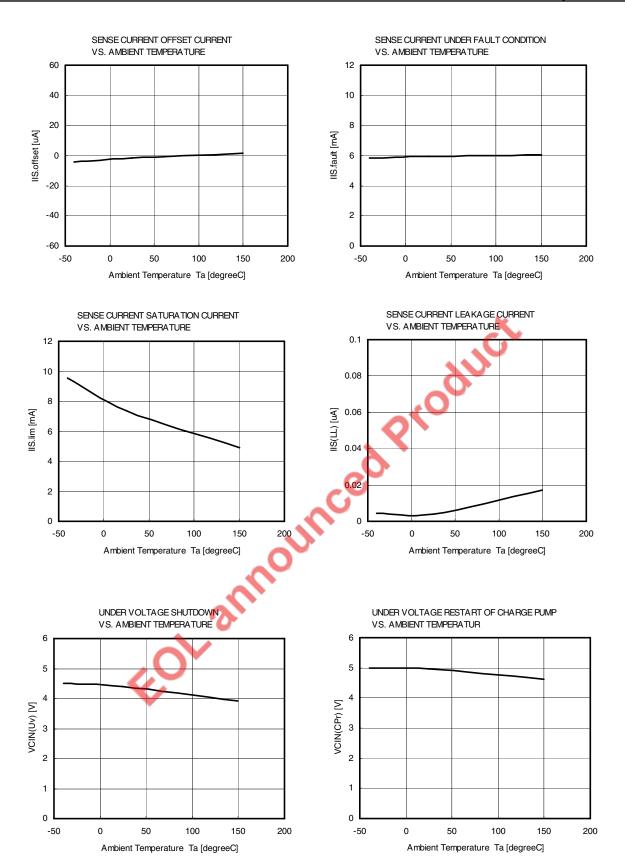
it is recommended to pull up the IN terminal to VCC using around 1 to 10 k Ω (approx.) resistor.

- If output current is over destruction current characteristics for inductive load at a single off, it must be connected through an external component for protection purpose.
- 3) If current sense and diagnostic features are not used, IS terminal has to be connected to GND via resistor.

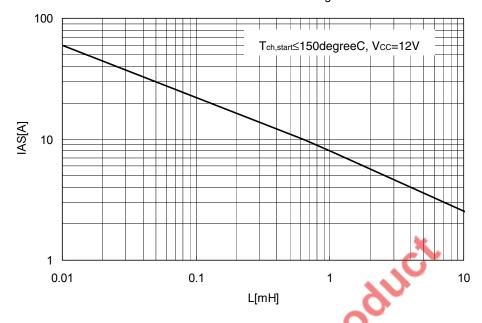
TYPICAL CHARACTERISTICS







INDUCTIVE LOAD SWITCH-OFF ENERGY DISSIPATION FOR A SINGLE PULSE



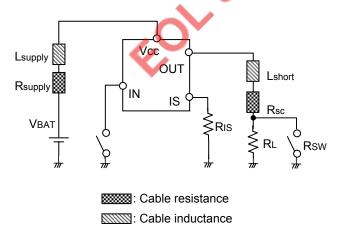
Maximum allowable load inductance for a single switch off

The energy dissipation for an inductive load switch-off single pulse in device (EAS1) is estimated by the following formula as $R_{L} = 0\Omega$.

$$EAS1 = \frac{1}{2} \cdot I^2 \cdot L \left(\frac{Von(CL)}{Von(CL) - VCC} \right)$$

MAXIMUM ALLOWABLE SWITCH OFF ENERGY (SINGLE PULSE)

The harness connecting the power supply, the load and the device has a small inductance and resistance. When the device turns off, the energy stored in the harness inductance is dissipated by the device, the harness resistance and the internal resistance of power supply. If the current is abnormally high due to a load short, the energy stored in the harness can be large. This energy has to be taken into consideration for the safe operation. The following figure shows the condition for Eas2, the maximum switch-off energy (single pulse) for abnormally high current.

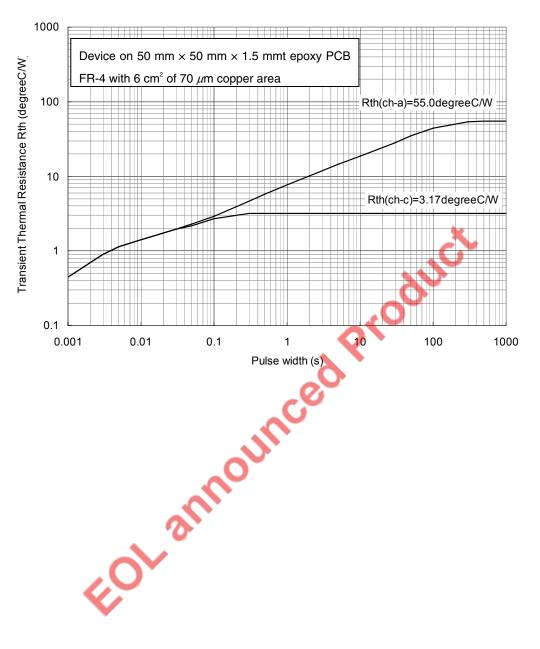


Vbat = 18 V,

 $\begin{aligned} & \text{Rsupply} = 10 \text{ m}\Omega, \text{ Rshort} = \text{Rsc} + \text{Rsw}_{(\text{on})} = 50 \text{ m}\Omega, \\ & \text{Lsupply} = 5 \ \mu\text{H}, \text{ Lshort} = 15 \ \mu\text{H}, \\ & \text{Tch,start} \leq 150^{\circ}\text{C} \end{aligned}$

THERMAL CHARACTERISTICS

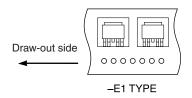
NEC



TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH

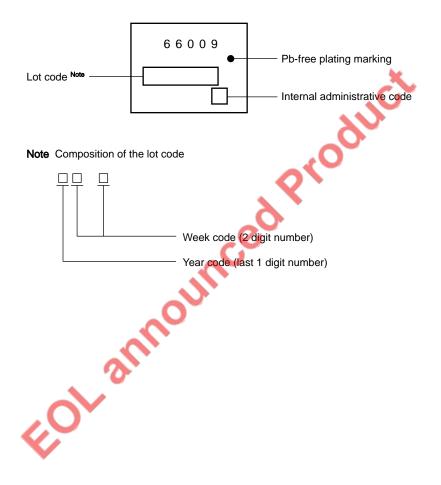
TAPING INFORMATION

This is one type (E1) of direction of the device in the career tape.



MARKING INFORMATION

This figure indicates the marking items and arrangement. However, details of the letterform, the size and the position aren't indicated.



REVISION HISTORY

Revision	Major changes since last version	Page
1st edition	Released 1st edition March 2009	
2nd edition	Released 2nd edition January 2010	
	Revised application example in principle	16

totamounced product

NOTES FOR CMOS DEVICES

- (1) VOLTAGE APPLICATION WAVEFORM AT INPUT PIN: Waveform distortion due to input noise or a reflected wave may cause malfunction. If the input of the CMOS device stays in the area between VIL (MAX) and VIH (MIN) due to noise, etc., the device may malfunction. Take care to prevent chattering noise from entering the device when the input level is fixed, and also in the transition period when the input level passes through the area between VIL (MAX) and VIH (MIN).
- (2) HANDLING OF UNUSED INPUT PINS: Unconnected CMOS device inputs can be cause of malfunction. If an input pin is unconnected, it is possible that an internal input level may be generated due to noise, etc., causing malfunction. CMOS devices behave differently than Bipolar or NMOS devices. Input levels of CMOS devices must be fixed high or low by using pull-up or pull-down circuitry. Each unused pin should be connected to VDD or GND via a resistor if there is a possibility that it will be an output pin. All handling related to unused pins must be judged separately for each device and according to related specifications governing the device.
- (3) PRECAUTION AGAINST ESD: A strong electric field, when exposed to a MOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it when it has occurred. Environmental control must be adequate. When it is dry, a humidifier should be used. It is recommended to avoid using insulators that easily build up static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work benches and floors should be grounded. The operator should be grounded using a wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions need to be taken for PW boards with mounted semiconductor devices.
- (4) STATUS BEFORE INITIALIZATION: Power-on does not necessarily define the initial status of a MOS device. Immediately after the power source is turned ON, devices with reset functions have not yet been initialized. Hence, power-on does not guarantee output pin levels, I/O settings or contents of registers. A device is not initialized until the reset signal is received. A reset operation must be executed immediately after power-on for devices with reset functions.
- (5) POWER ON/OFF SEQUENCE: In the case of a device that uses different power supplies for the internal operation and external interface, as a rule, switch on the external power supply after switching on the internal power supply. When switching the power supply off, as a rule, switch off the external power supply and then the internal power supply. Use of the reverse power on/off sequences may result in the application of an overvoltage to the internal elements of the device, causing malfunction and degradation of internal elements due to the passage of an abnormal current. The correct power on/off sequence must be judged separately for each device and according to related specifications governing the device.
- (6) INPUT OF SIGNAL DURING POWER OFF STATE : Do not input signals or an I/O pull-up power supply while the device is not powered. The current injection that results from input of such a signal or I/O pull-up power supply may cause malfunction and the abnormal current that passes in the device at this time may cause degradation of internal elements. Input of signals during the power off state must be judged separately for each device and according to related specifications governing the device.

- The information in this document is current as of January, 2010. The information is subject to change without notice. For actual design-in, refer to the latest publications of NEC Electronics data sheets or data books, etc., for the most up-to-date specifications of NEC Electronics products. Not all products and/or types are available in every country. Please check with an NEC Electronics sales representative for availability and additional information.
- No part of this document may be copied or reproduced in any form or by any means without the prior written consent of NEC Electronics. NEC Electronics assumes no responsibility for any errors that may appear in this document.
- NEC Electronics does not assume any liability for infringement of patents, copyrights or other intellectual property rights of third parties by or arising from the use of NEC Electronics products listed in this document or any other liability arising from the use of such products. No license, express, implied or otherwise, is granted under any patents, copyrights or other intellectual property rights of NEC Electronics or others.
- Descriptions of circuits, software and other related information in this document are provided for illustrative purposes in semiconductor product operation and application examples. The incorporation of these circuits, software and information in the design of a customer's equipment shall be done under the full responsibility of the customer. NEC Electronics assumes no responsibility for any losses incurred by customers or third parties arising from the use of these circuits, software and information.
- While NEC Electronics endeavors to enhance the quality, reliability and safety of NEC Electronics products, customers agree and acknowledge that the possibility of defects thereof cannot be eliminated entirely. To minimize risks of damage to property or injury (including death) to persons arising from defects in NEC Electronics products, customers must incorporate sufficient safety measures in their design, such as redundancy, fire-containment and anti-failure features.
- NEC Electronics products are classified into the following three quality grades: "Standard", "Special" and "Specific". The "Specific" quality grade applies only to NEC Electronics products developed based on a customer-designated "quality assurance program" for a specific application. The recommended applications of an NEC Electronics product depend on its quality grade, as indicated below. Customers must check the quality grade of each NEC Electronics product before using it in a particular application.
- "Standard": Computers, office equipment, communications equipment, test and measurement equipment, audio and visual equipment, home electronic appliances, machine tools, personal electronic equipment and industrial robots.
- "Special": Transportation equipment (automobiles, trains, ships, etc.), traffic control systems, anti-disaster systems, anti-crime systems, safety equipment and medical equipment (not specifically designed for life support).
- "Specific": Aircraft, aerospace equipment, submersible repeaters, nuclear reactor control systems, life support systems and medical equipment for life support, etc.

The quality grade of NEC Electronics products is "Standard" unless otherwise expressly specified in NEC Electronics data sheets or data books, etc. If customers wish to use NEC Electronics products in applications not intended by NEC Electronics, they must contact an NEC Electronics sales representative in advance to determine NEC Electronics' willingness to support a given application.

- (Note 1) "NEC Electronics" as used in this statement means NEC Electronics Corporation and also includes its majority-owned subsidiaries.
- (Note 2) "NEC Electronics products" means any product developed or manufactured by or for NEC Electronics (as defined above).